

L Number	Hits	Search Text	DB	Time stamp
15	0	choos\$5 near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:41
36	0	choice near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:43
43	1	model near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:45
50	4628	model near model	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:47
57	17	(model near model) and inspection and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:47
64	363	die near model	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:47
71	9	(die near model) and inspection and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:47
22	6	determin\$5 near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:49
29	1	decid\$5 near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:50
78	902	(reference or model) near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:51
85	13730	compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:57
92	10117	die near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 12:57
99	199	((reference or model) near die) and ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 13:04
106	58	((reference or model) near die) and ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/21 13:04

113,	47	((reference or model) near die) same ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/21 13:04
120	23	((reference or model) near die) same ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/21 13:04
-	5	select\$5 near reference near die	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/21 12:41
-	1	2000-656045.NRAN.	DERWENT	2003/05/20 14:42
-	507	(382/145,149).CCLS.	USPAT	2003/05/20 14:44
-	34	(known or good or defect) with reference near die	USPAT	2003/05/20 14:45
-	5	(known or good or defect) near2 reference near die	USPAT	2003/05/20 14:45
-	13	((382/145,149).CCLS.) and reference near die	USPAT	2003/05/20 15:32
-	25	((known or good or defect) with reference near die) not (((382/145,149).CCLS.) and reference near die)	USPAT	2003/05/20 15:32